

Search Notes

Application/Control No.

10/821,909

Examiner

Hieu Nguyen

Applicant(s)/Patent under
Reexamination

DOI, YOSHIAKI

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	124R	9/1/2005	HN
330	295	9/7/2005	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	9/1/2005	HN
NGUYEN KHANH V	9/1/2005	HN